Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/781,387	JEONG ET AL.
Examiner	Art Unit
PHUC H. TRAN	2616

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
·	DATE	EXMR
East text search 370/321,337,347- 348, 442-444	9/25/2007	PT